

**Search Notes**

Application/Control No.

10/790,130

Examiner

David J. Makiya

Applicant(s)/Patent under  
Reexamination

FANG, TE-HSIANG

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	118	7/5/2005	DJM
362	810	7/5/2005	DJM
362	205	7/1/2005	DJM
401	104	7/1/2005	DJM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Key Words Searched in EAST (see attached)	7/1/2005	DJM